

<b>Notice of References Cited</b>	Application/Control No. 10/779,559	Applicant(s)/Patent Under Reexamination FURUKAWA ET AL.	
	Examiner Sang Y Paik	Art Unit 3742	Page 1 of 1

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	C	US-6,359,264	03-2002	Schaper et al.	219/444.1
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